Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/785,445	WANG ET AL
Examiner	Art Unit
Matthew D. Matzek	1771

	SEAR	CHED	
Class	Subclass	Date	Examiner
445	82,88,94	11/20/05	мм
977	016.1	11/30/05	ил
428	400	11/30/05	им
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442	221		
	268 286		
	315		
	370 381		
	394		
428	174~		
	180~		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EHST	14,/05	мм
INVENTOR / ASSIGNE	11/30/15	אניע
105	12/1/05	мм